



# **Thin-Film Semiconductor Technology Applied to Large Area Radiation Detectors**

**CIRMS Conference 2012**

**October 23, 2012**

Bruce Gnadé  
UT Dallas

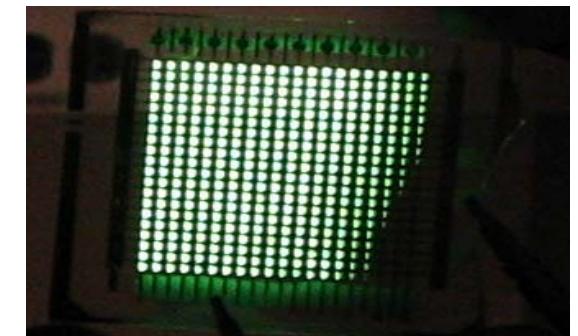
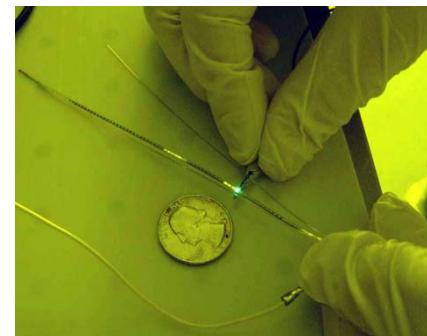
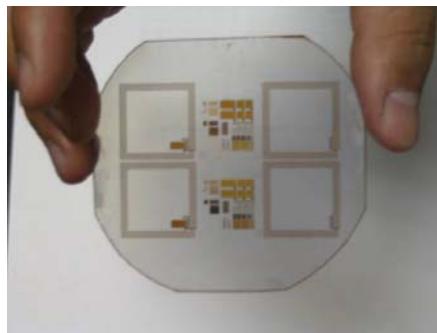
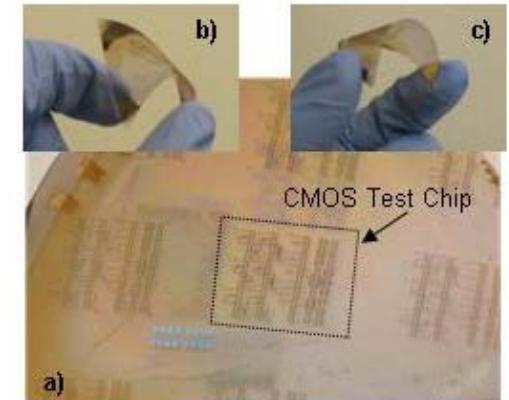


# Flexible Electronics Research Group at UTD

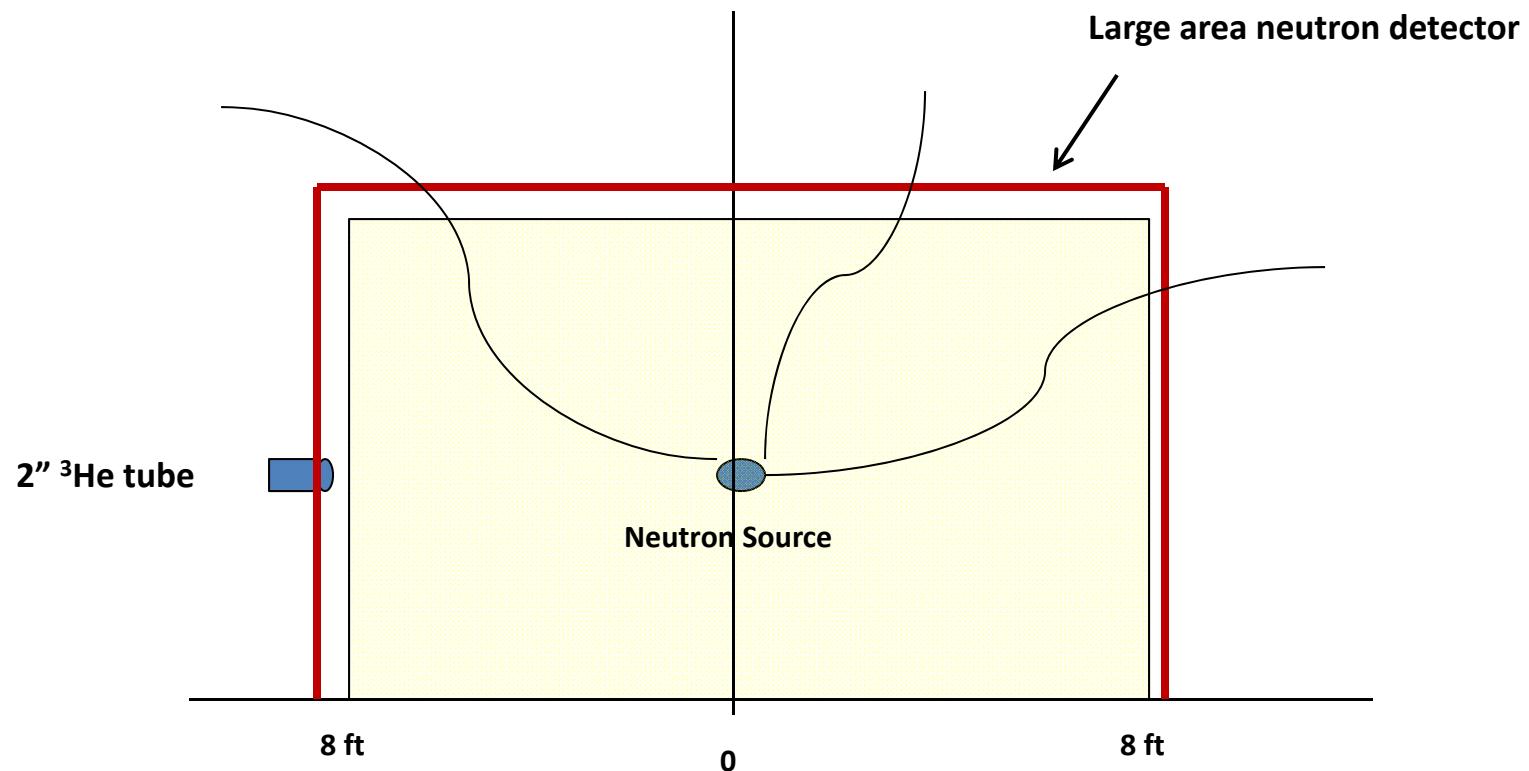
- **POST-DOCS/STAFF SCIENTISTS**
  - Dr. I. Mejia, Dr. Kurtis Cantley, Dr. M. Jia, Dr. I. Trachtenberg, Dr. A. Carrillo, Dr. N. Hernandez, Dr. J. Conde, Dr. Dick Chapman
- **GRADUATE STUDENTS/PROJECTS**
  - Ana Salas – PhD. – Alternate Contacts (AFOSR)
  - Duo Mao – Ph.D. – Organic Memory (ARL)
  - Mike Perez, Ph.D. – n-type flexible TFTs (NSF)
  - John Murphy Ph.D – Large Area Neutron Detectors (ARL, FUSION)
  - Martha Rivas – Pulsed Laser Deposition of Chalcogenides
  - Dewan Lutful Kabir – Reliability and Electrical Characterization
  - Lindsey Smith – Neutron converter layers (DNDO)
  - Kevin Larosa – Backplane electronics (DNDO)
- **VISITING SCHOLARS**
  - J. Ramos (UACJ), V. Martinez, (CIMAV), G. Gutierrez (CIMAV), Alfredo Luque (CNyN)
- **Collaborators**
  - Dr. David Allee (ASU), Dr. Eric Forsythe (ARL), George Kunnen (ASU)
- **FUNDING**
  - U.S. Army Research Labs, Military Tech, DOE, UT Dallas, Texas MicroPower, NSF, Texas Instruments, FUSION, DNDO, AFOSR, DARPA

# Agenda

- Large Area Radiation Detectors
  - Why thin-film devices
  - Large area neutron detector project
- Current state of thin-film semiconductor devices
  - Transistors
  - Memory
  - CMOS
  - Circuits



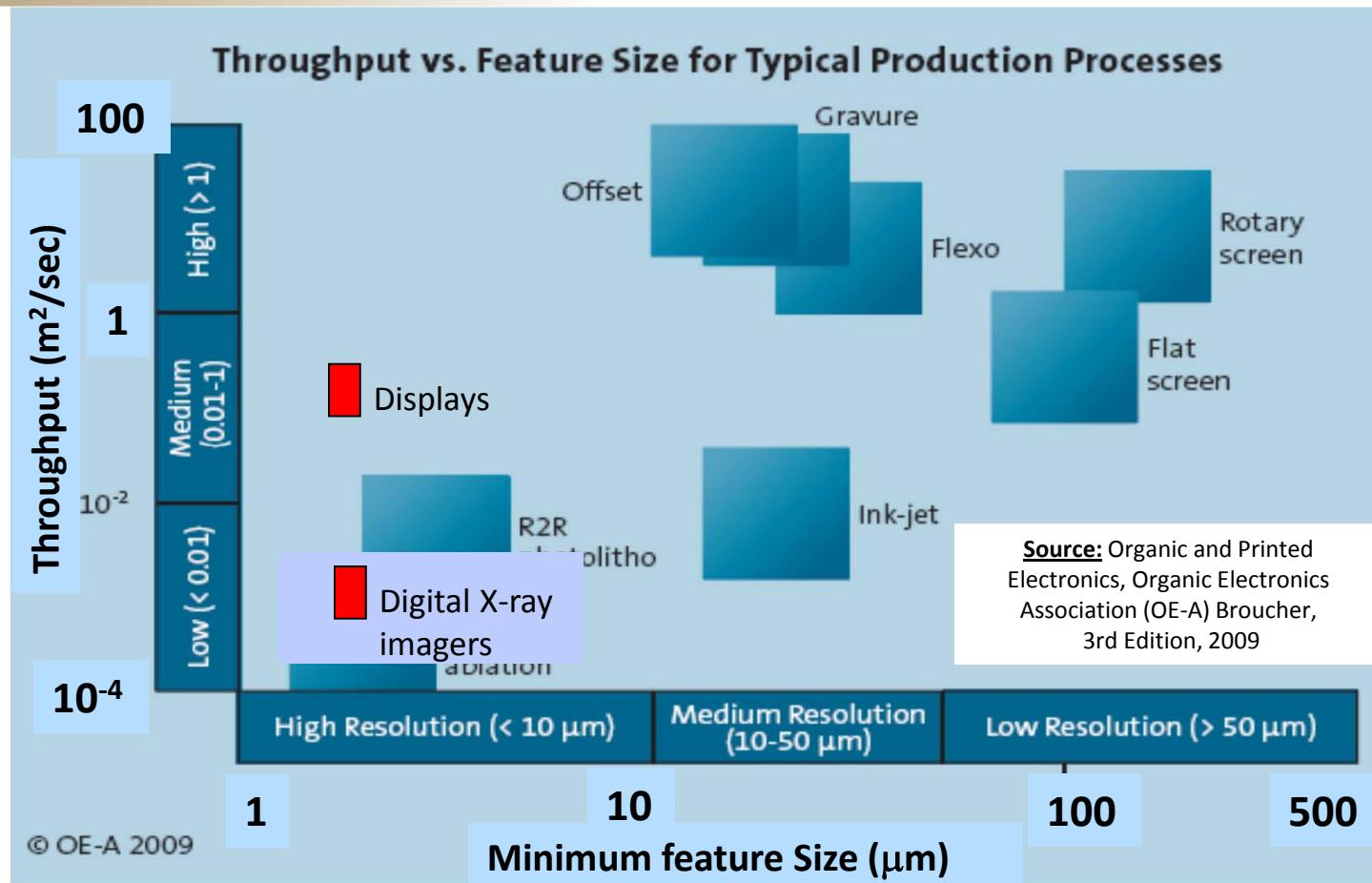
# Why large area detectors?



Probability of neutron hitting 2" tube ~ 1 part in 36000

Probability of neutron hitting large area detector ~ 1 part in 3

# Future Flexible Electronics Throughput vs cost/cm<sup>2</sup>



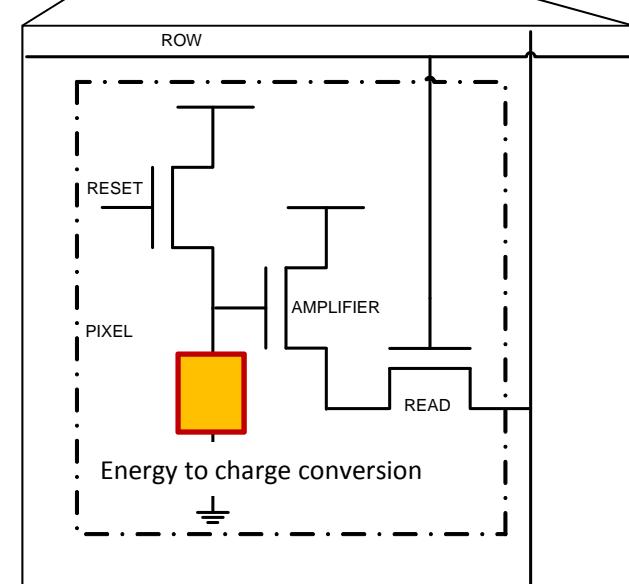
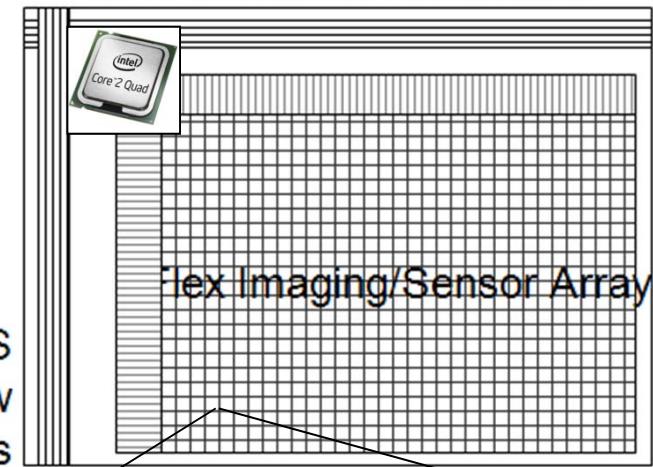
Thanks to Dr. Eric Forsythe – Army Research Laboratory



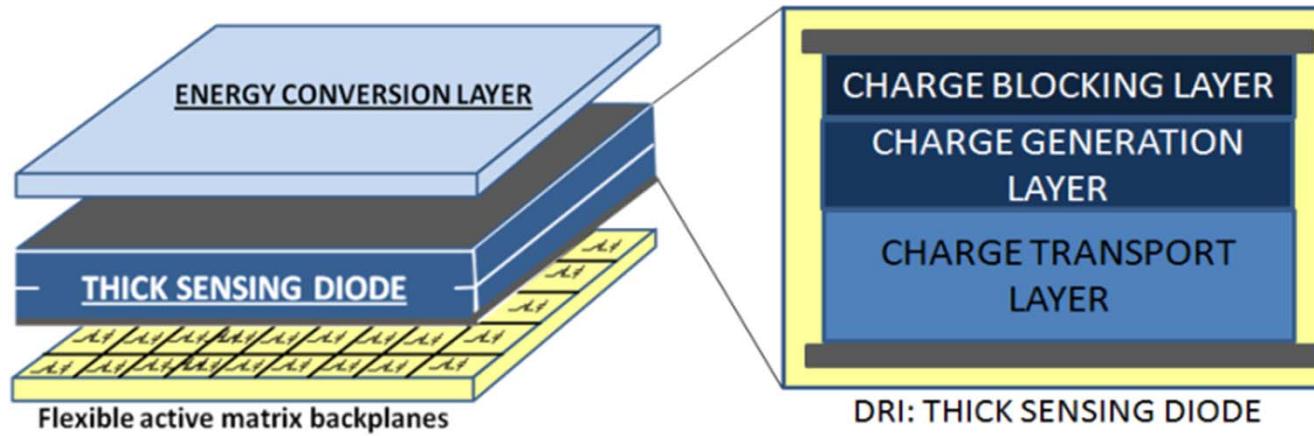
COTS µC

COTS Column Electronics

COTS  
Row  
Electronics



- ***Neutron Detection***
- VIS / IR Imager
- Millimeter Wave
- *MEMS*
  - *Blast*
  - *Acoustic*
- Electronic Textiles

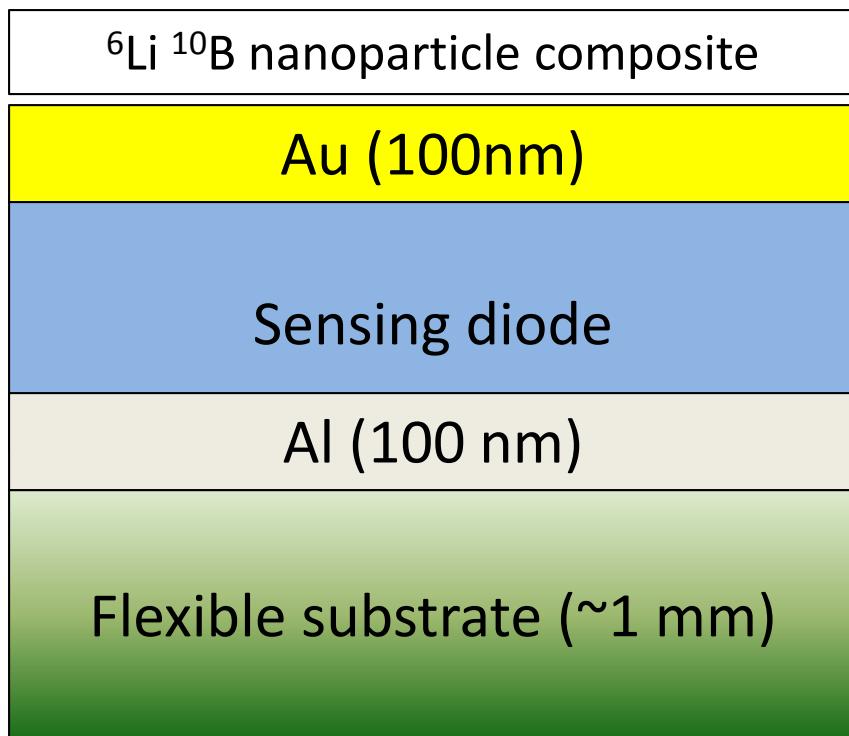


## Three main pieces

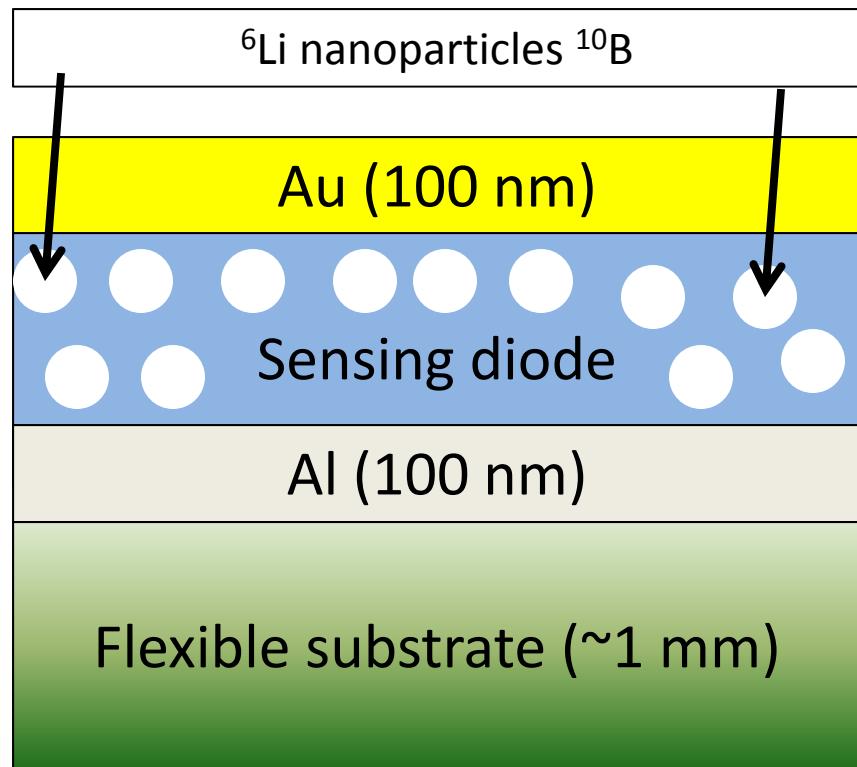
- energy conversion layer
- sensing diode
- backplane electronics

Isotope	Reaction	Thermal $\sigma$ (barns)	Charged particles and energies (keV)
$^3\text{He}$	$^3\text{He}(\text{n},\text{p})^3\text{H}$	5333	p: 573, $^3\text{H}$ : 191
$^6\text{Li}$	$^6\text{Li}(\text{n},\alpha)^3\text{H}$	940	$^3\text{H}$ : 2727, $\alpha$ : 2055
$^{10}\text{B}$	$^{10}\text{B}(\text{n},\alpha)^7\text{Li}$	3835	$\alpha$ : 1472, $^7\text{Li}$ : 480
$^{\text{nat}}\text{Gd}$	$^{\text{nat}}\text{Gd}(\text{n},\gamma)$	49700	Conversion e-: 29-191
$^{157}\text{Gd}$	$^{157}\text{Gd}(\text{n},\gamma)$	259000	Conversion e-: 29-182
$^{235}\text{U}$	$^{235}\text{U}(\text{n},\text{f})$	681	Various fission products

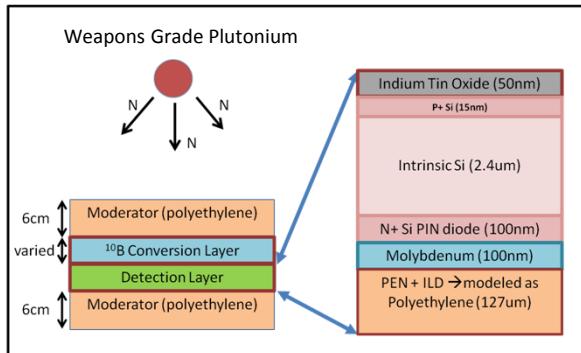
**Converter-on-diode**



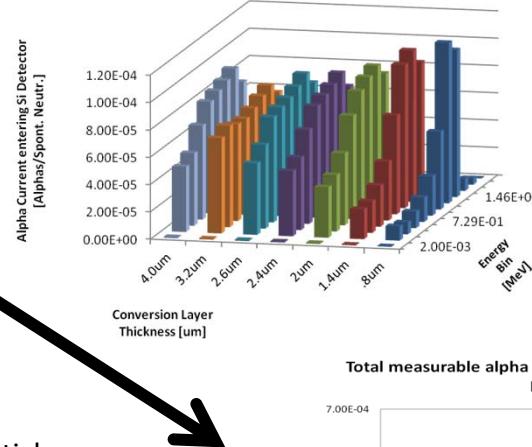
**Converter-in-diode**



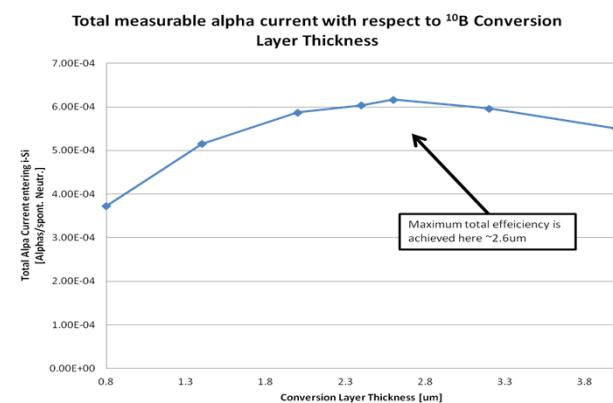
## Detector Layers simulated in MCNPX:



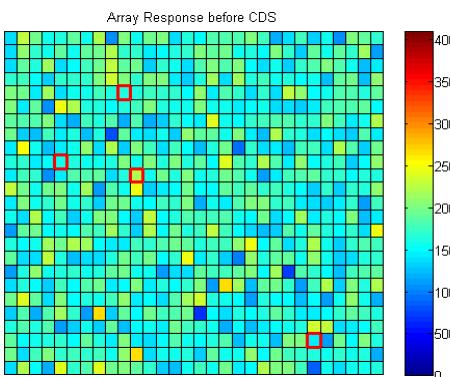
- Front end captures Neutron and emits charged alpha particle,
- Alpha detected with PIN diode and active pixel sensor circuit
- MCNPX used to model and optimize detector front-end layers
- Detector layers capable of being fabricated with FDC process



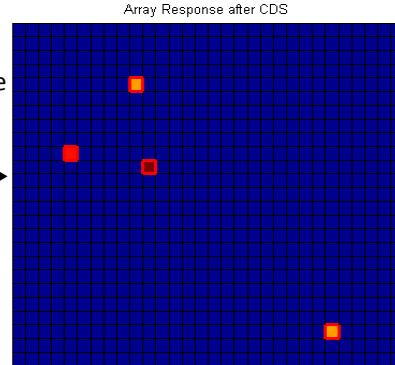
→ Example neutron conversion layer optimizations result in 2.6um  $^{10}\text{B}$  thickness



## MATLAB model of arrayed pixel sensors with simulated alpha particle exposure (Red Boxes):



With Correlated Double Sampling applied:



- Each cell represents an active pixel sensor
- Sensors modeled to reflect FDC process variations.
- CDS dramatically improves ability for detector to resolve alpha particle strikes

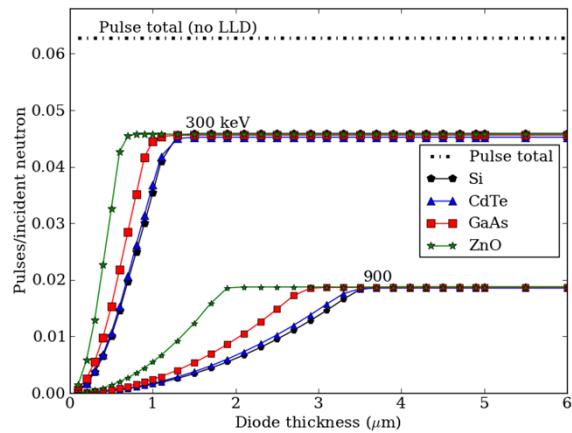
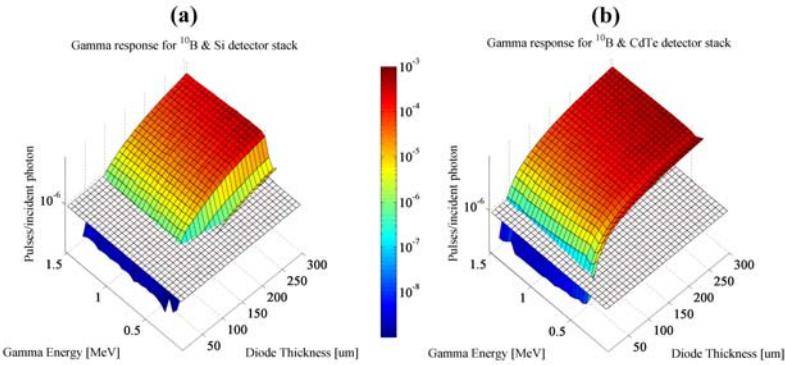
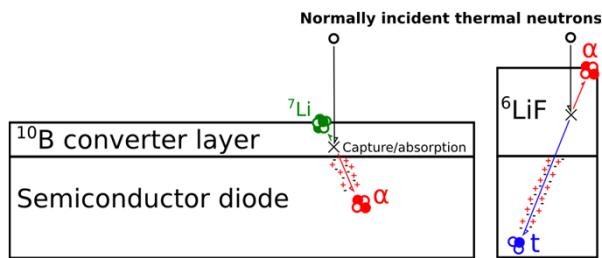
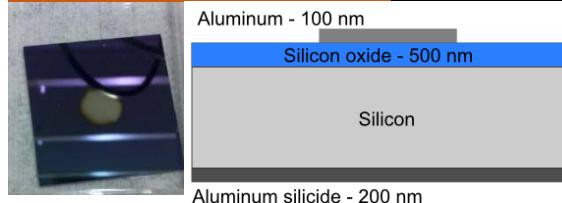


TABLE II. Intrinsic gamma efficiencies for selected thicknesses and gamma energies. (LLD = 300keV and a  $2.8 \mu\text{m}$   $^{10}\text{B}$  conversion layer)

Thickness ( $\mu\text{m}$ )	$\gamma$ energy (keV)	Si	CdTe	GaAs	ZnO
3	511	0	0	0	0
	1460	0	$9 \times 10^{-14}$	0	$8 \times 10^{-14}$
10	511	0	$6 \times 10^{-13}$	0	$1 \times 10^{-12}$
	1460	$1 \times 10^{-13}$	$9 \times 10^{-12}$	$2 \times 10^{-12}$	$8 \times 10^{-12}$
30	511	$6 \times 10^{-11}$	$6 \times 10^{-7}$	$1 \times 10^{-7}$	$3 \times 10^{-7}$
	1460	$1 \times 10^{-10}$	$2 \times 10^{-7}$	$6 \times 10^{-8}$	$2 \times 10^{-7}$
100	511	$3 \times 10^{-6}$	$4 \times 10^{-4}$	$2 \times 10^{-4}$	$2 \times 10^{-4}$
	1460	$2 \times 10^{-6}$	$1 \times 10^{-4}$	$6 \times 10^{-5}$	$9 \times 10^{-5}$
300	511	$3 \times 10^{-4}$	$4 \times 10^{-3}$	$2 \times 10^{-3}$	$2 \times 10^{-3}$
	1460	$2 \times 10^{-4}$	$3 \times 10^{-3}$	$2 \times 10^{-3}$	$2 \times 10^{-3}$

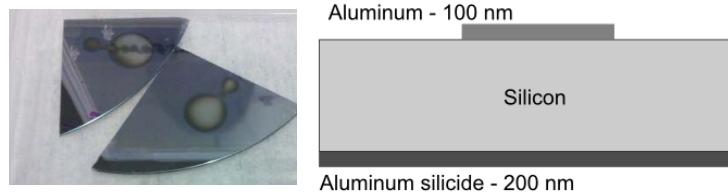


# Sensing Diode Optimization: Schottky vs. MIS



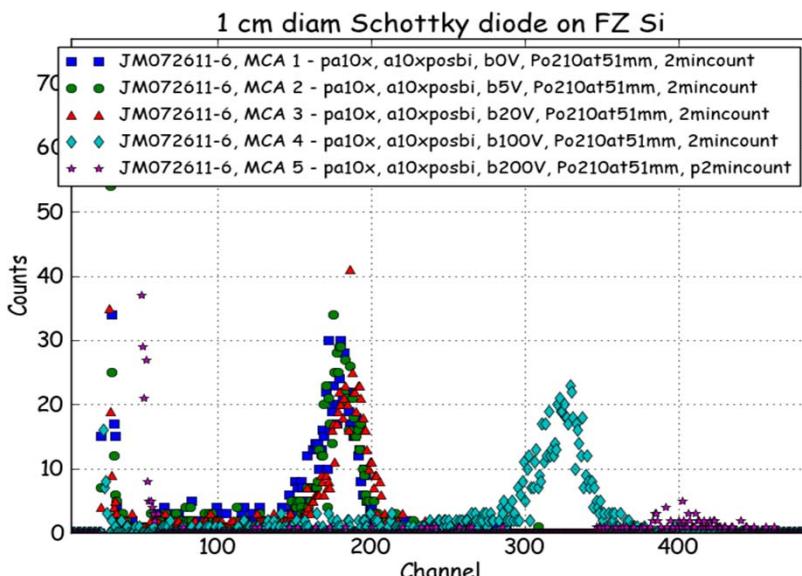
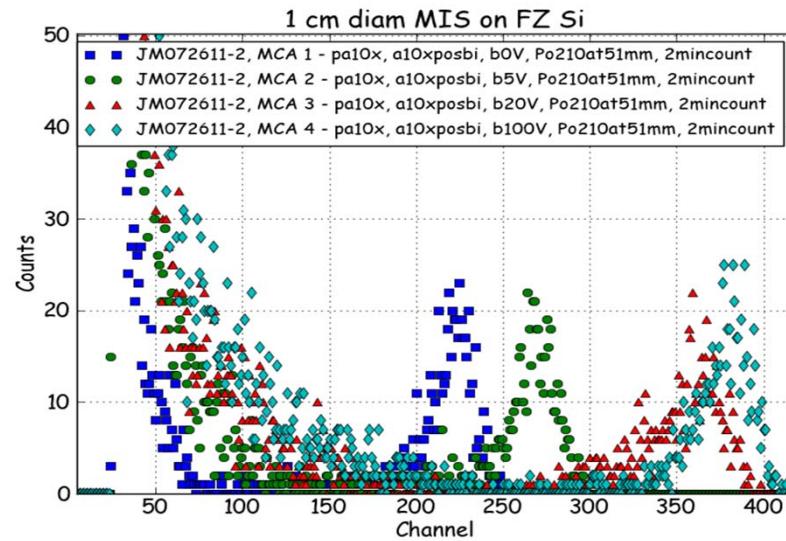
Integrating over channels for peak

Detector bias (V)	0V	5V	20V
Particles detected	562	595	651
Measured source strength	1,938	1,954	2,245
Efficiency	<b>60%</b>	<b>60%</b>	<b>69%</b>

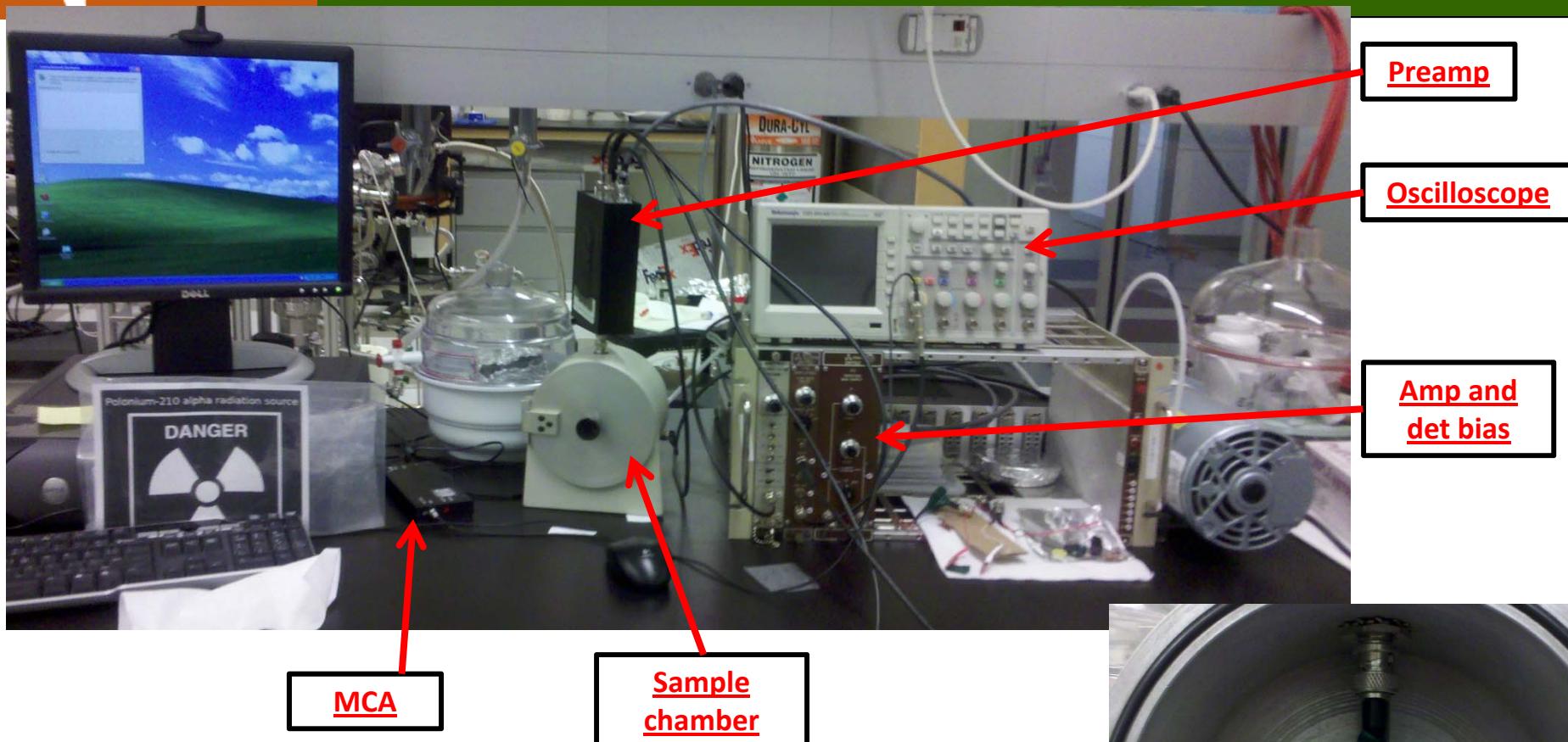


Integrating over channels 100-450

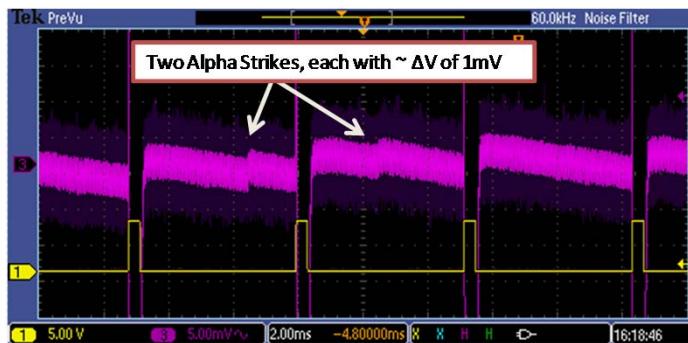
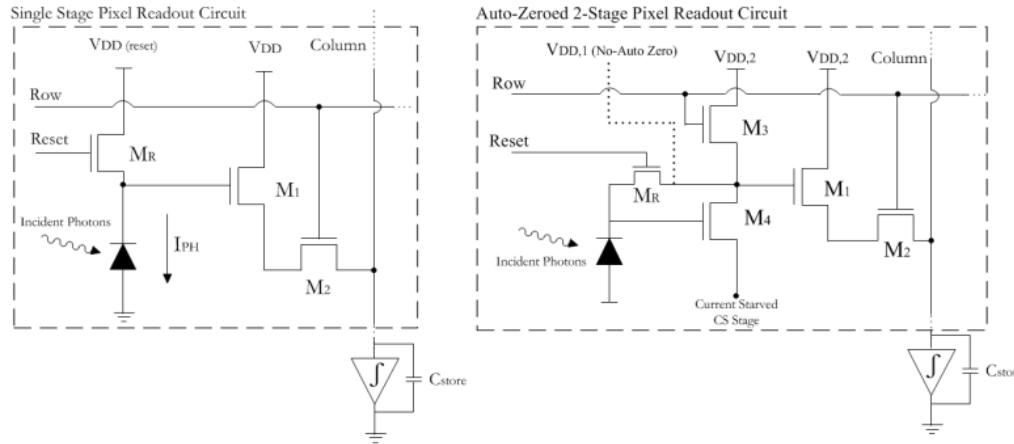
Detector bias (V)	0V	5V	20V	100V
Particles detected	785	772	752	869
Measured source strength	2,486	2,445	2,382	2,752
Efficiency	<b>77%</b>	<b>76%</b>	<b>74%</b>	<b>85%</b>



# Radiation measurement setup

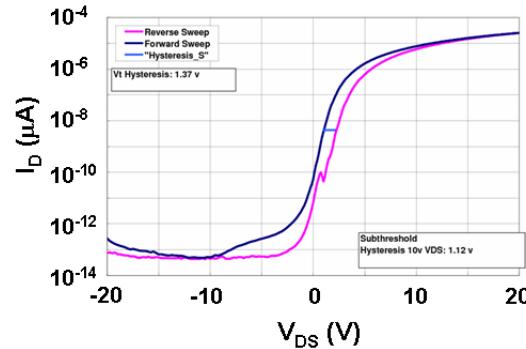
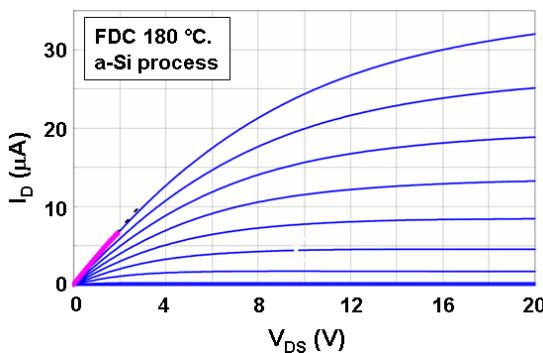
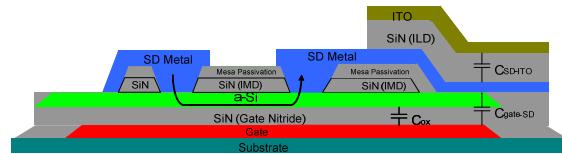


# TFT-based Active Pixel Sensors

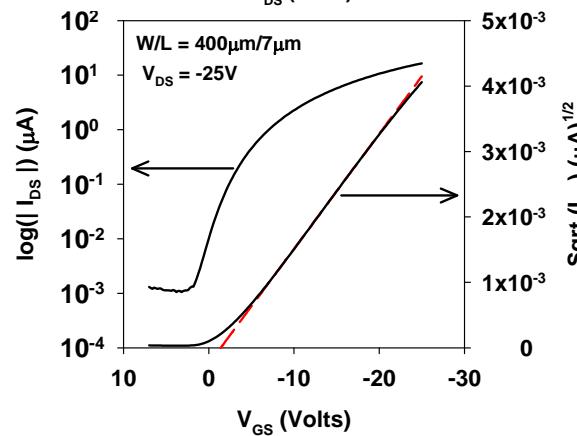
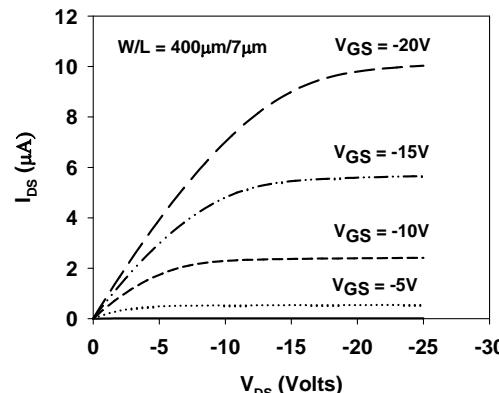
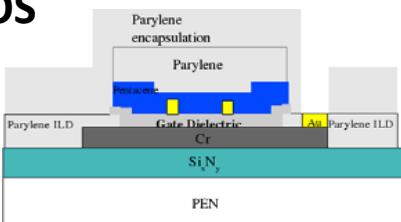


The detection of two alpha particle strikes on a commercial diode and amplified with the two stage low noise thin film transistor amplifier.

## NMOS



## PMOS



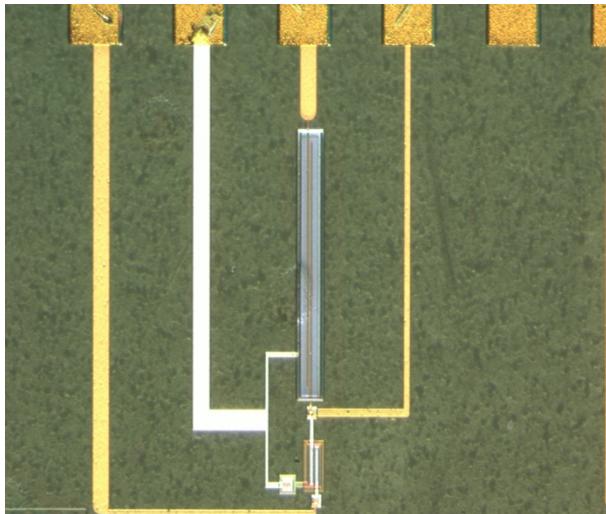
## Why CMOS

- Dramatically reduced power consumption
- Analog circuitry possible
- Sensor applications

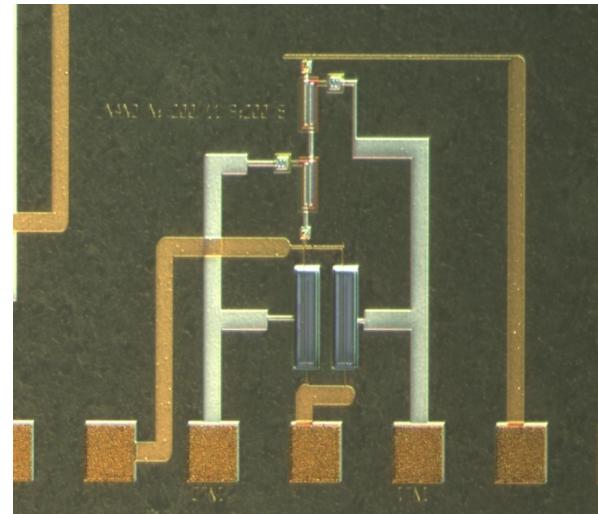
## How to do F-CMOS

- Combine Processes
  - N-Type a-Si:H TFTs
  - N-Type inorganic TFTs
  - P-Type Organic TFTs
- Standard Cell Approach

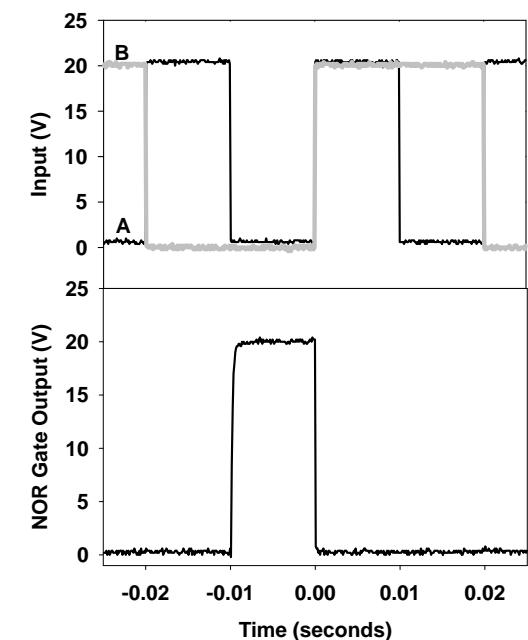
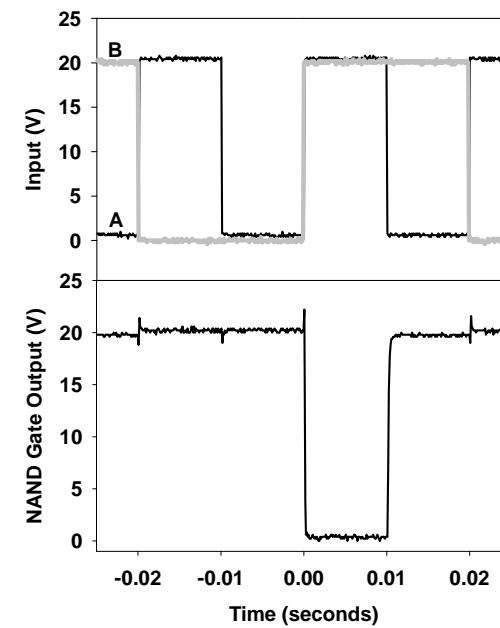
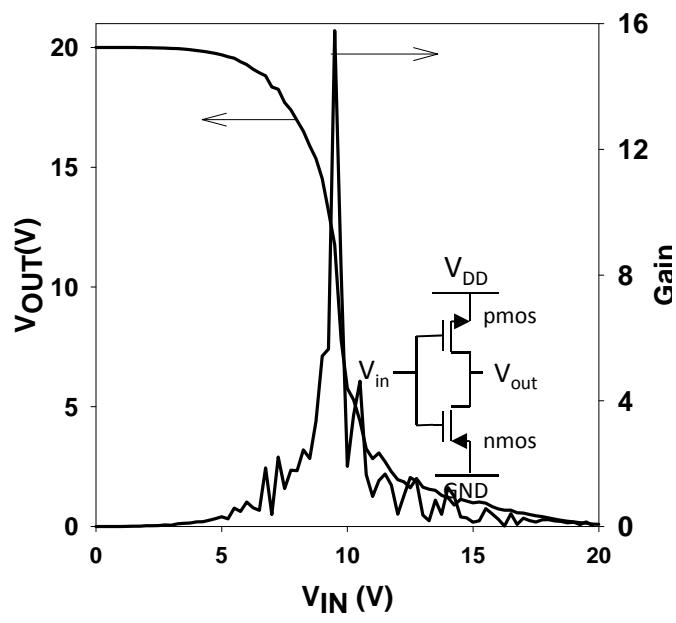
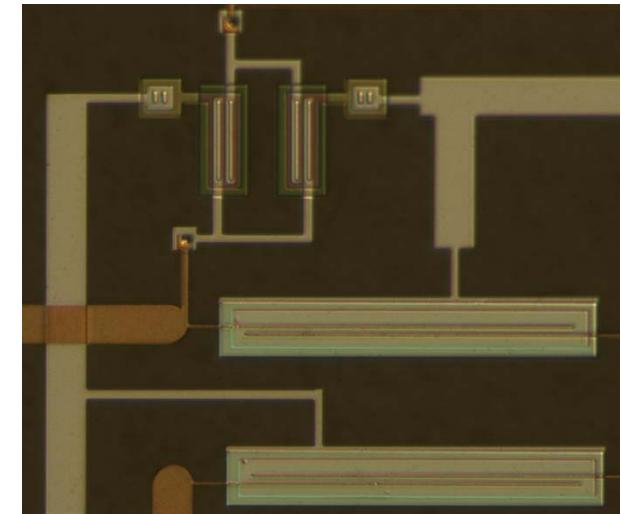
**Inverters**



**NAND Gates**



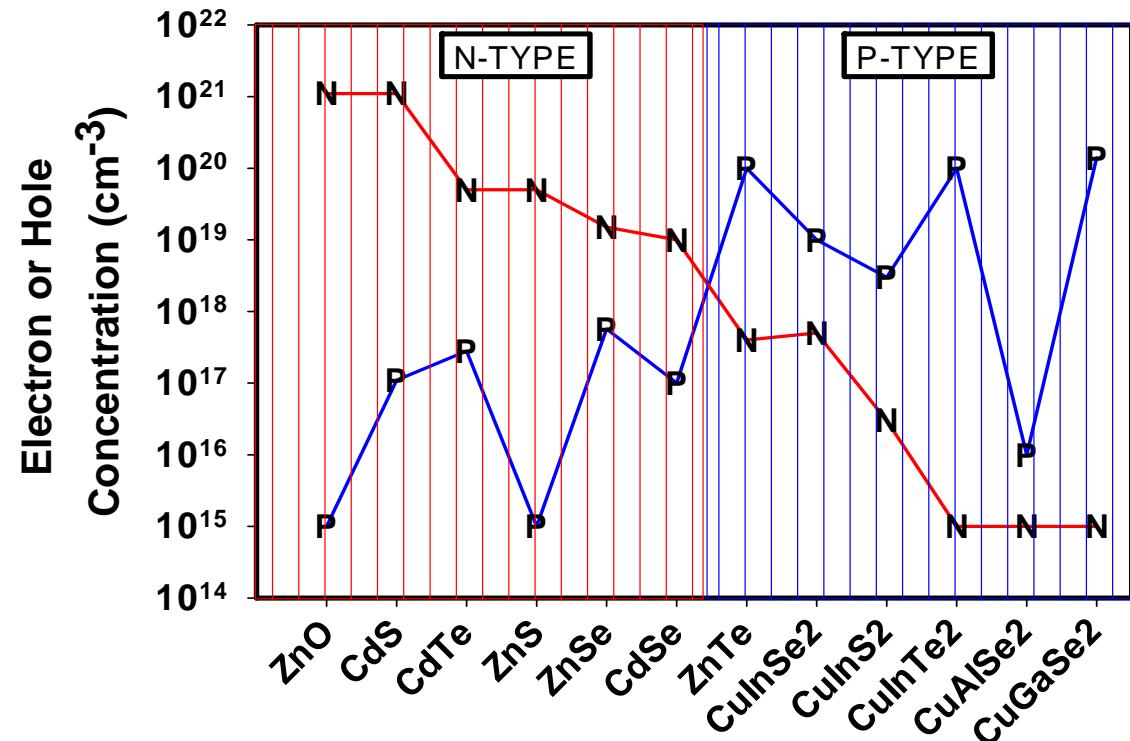
**NOR Gates**



# Technology Comparison

## Chalcogenides

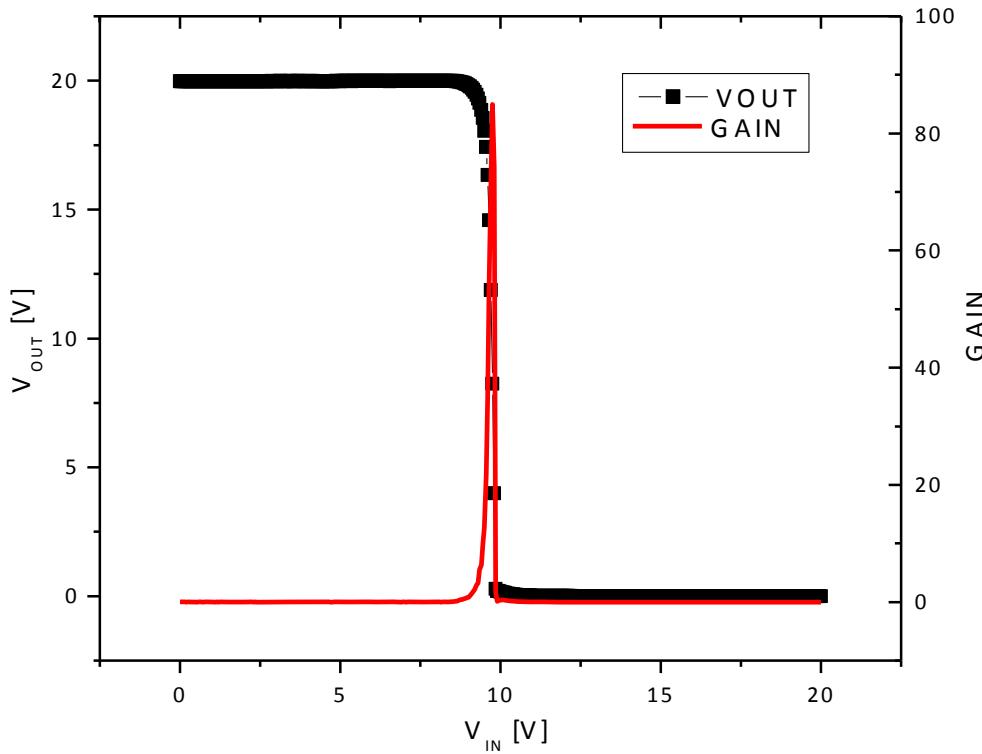
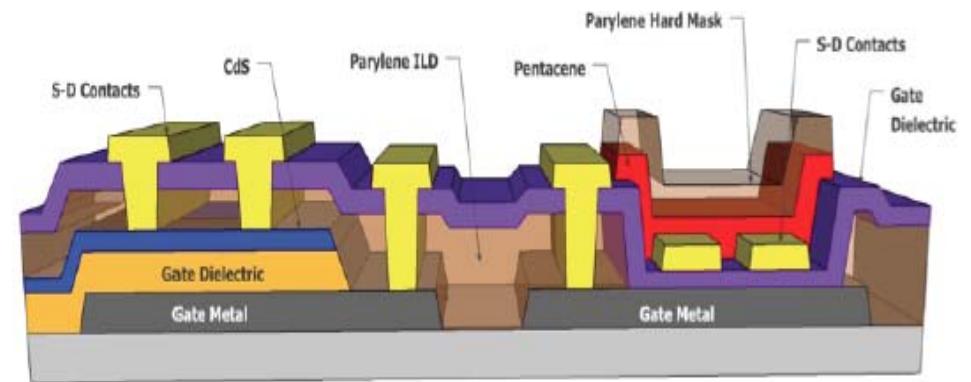
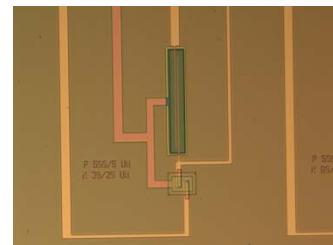
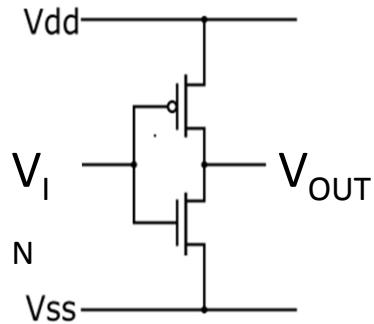
Semiconductor	Mobility (cm <sup>2</sup> /V-s)	
	e <sup>-</sup>	h <sup>+</sup>
CdS	250	
CdSe	650	
ZnSe	600	
SnSe <sub>2</sub>	27	
InS	50	
SnS <sub>2</sub>	18	
CuGaS <sub>2</sub>		20
CuInS <sub>2</sub>		15
ZnTe		100
PbS		5
Cu <sub>2</sub> S		10



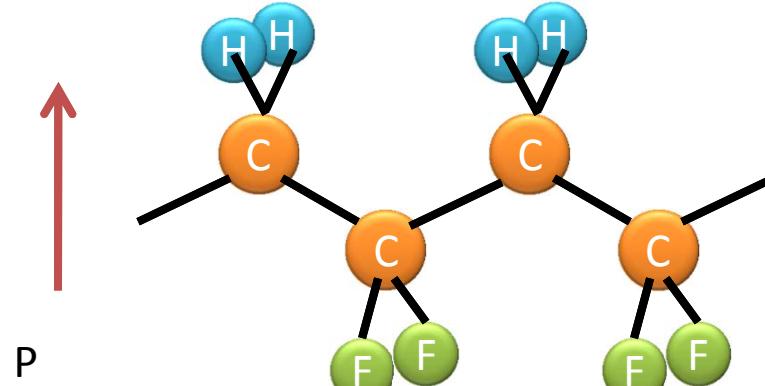
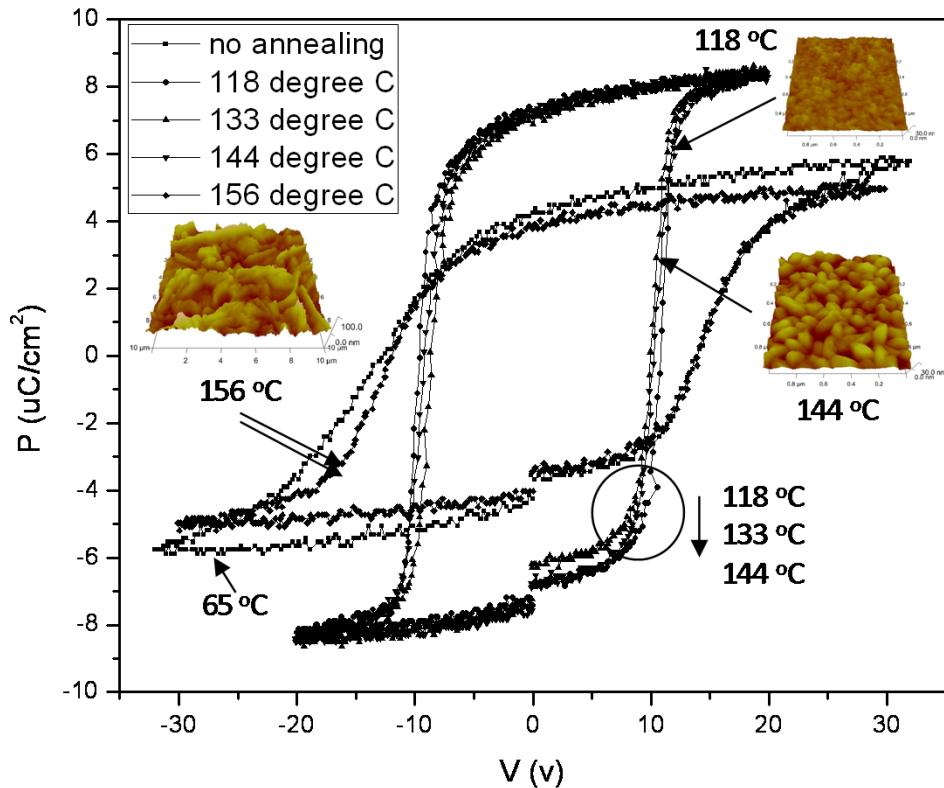
**Organic semiconductors**  $\mu \sim 6 \times 10^{-2}$  to  $1 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$

**Amorphous silicon:**  $\mu \sim 0.01$  to  $1 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$

**Inorganic semiconductors:**  $\mu > 100 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$

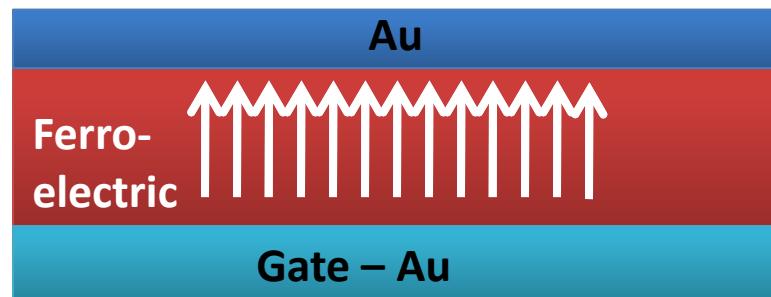


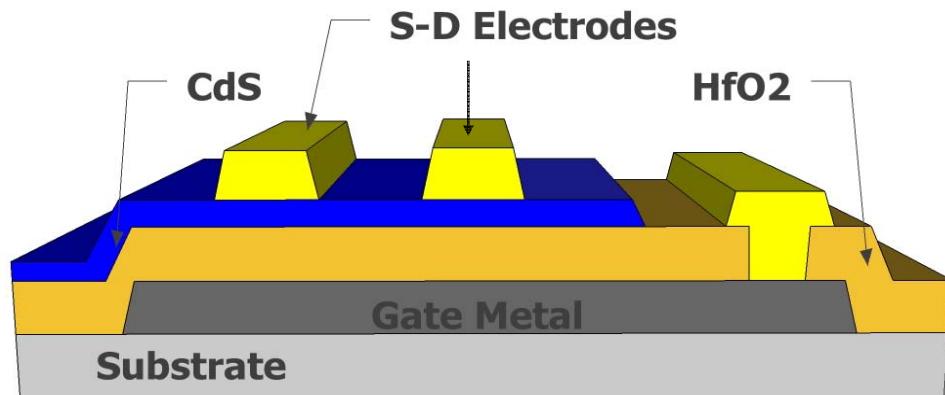
- Optimized pentacene and CBD CdS deposition
- Inverters yield gains of about 80



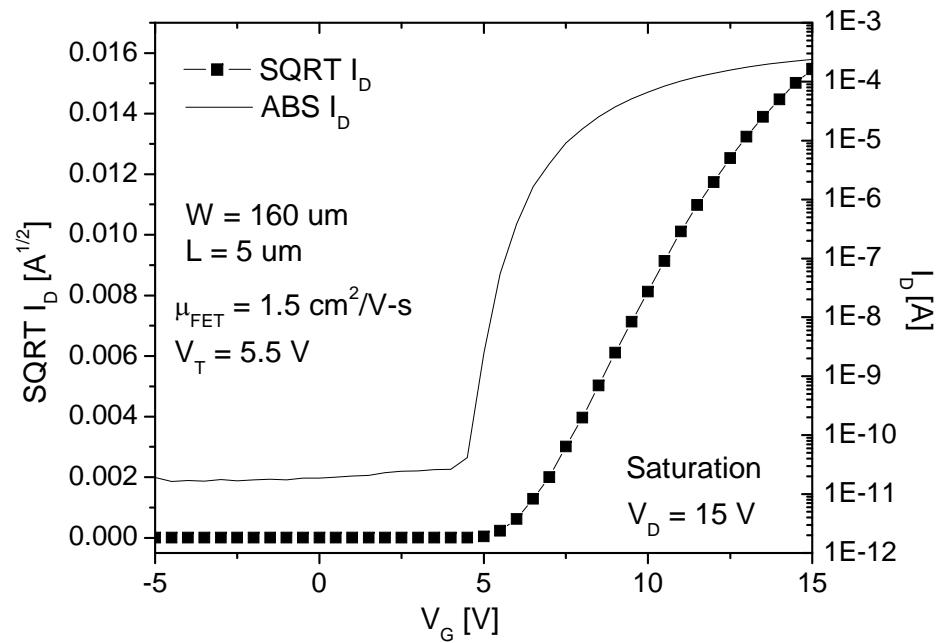
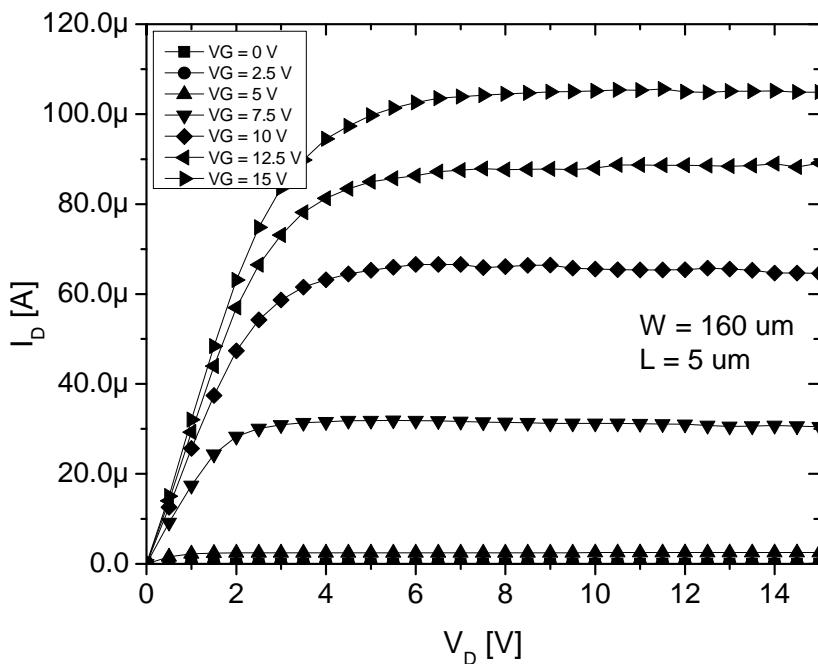
**MFM Capacitor – 1T-1C memory cell**

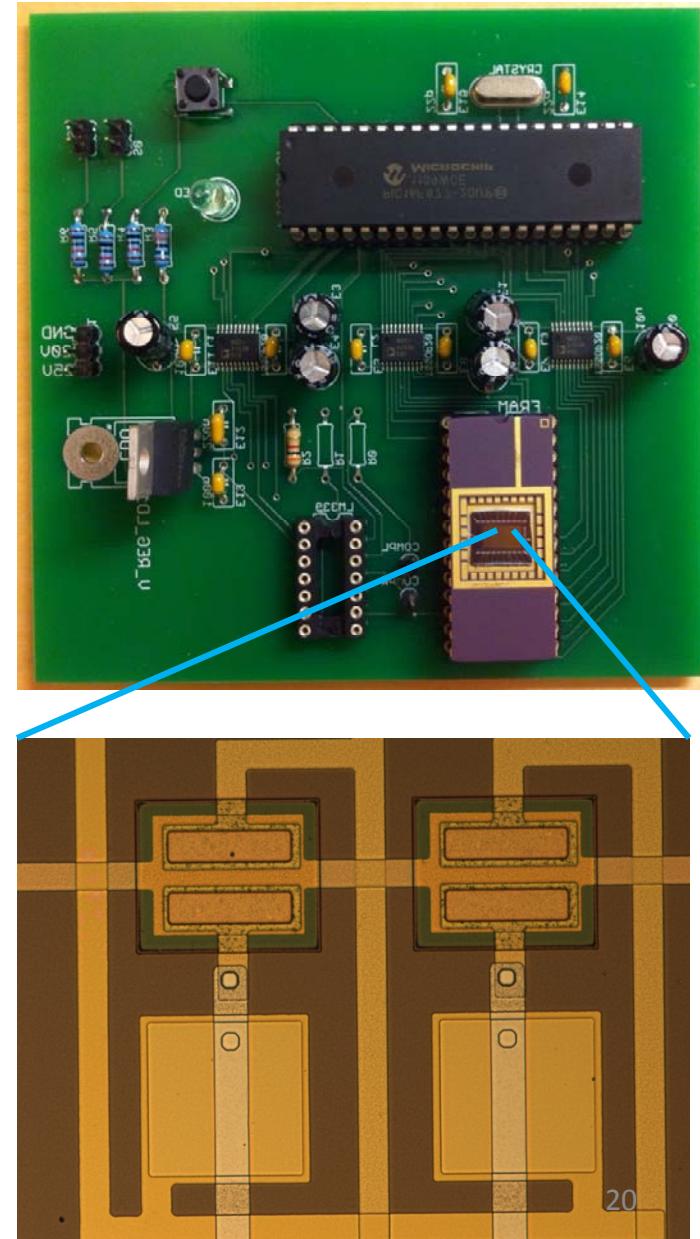
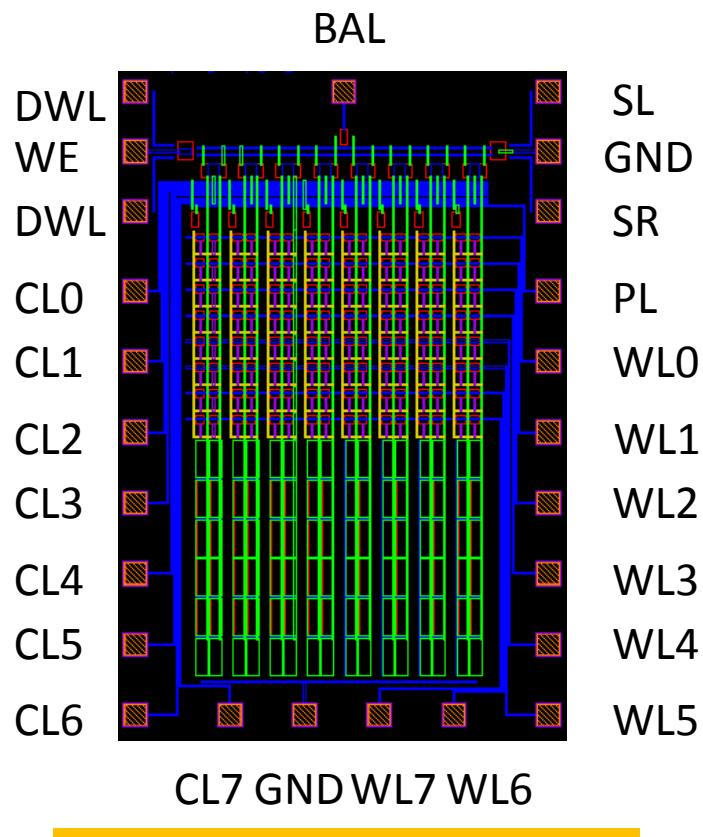
- relatively easy to fabricate
- destructive read
- complicated read / write circuitry





1. CBD CdS as the semiconductor
2. ALD HfO<sub>2</sub> as the gate dielectric
3. Parylene as ILD
4. Low temperature process,  
maximum temperature is 100 °C

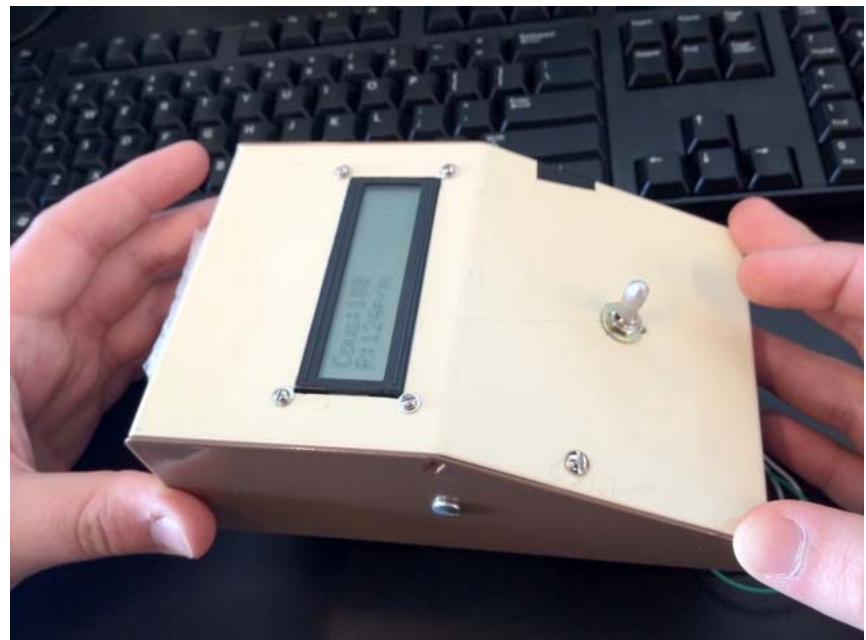
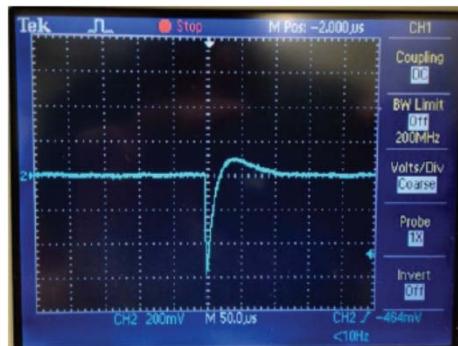
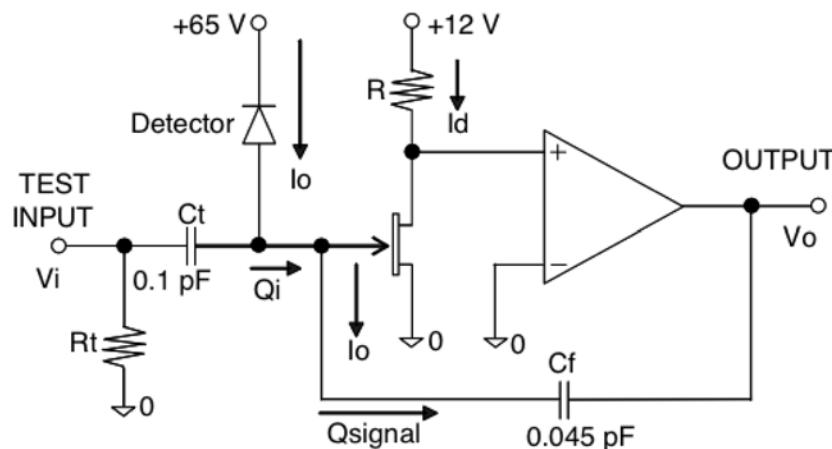




# In-pixel charge amplifier – Ramirez design

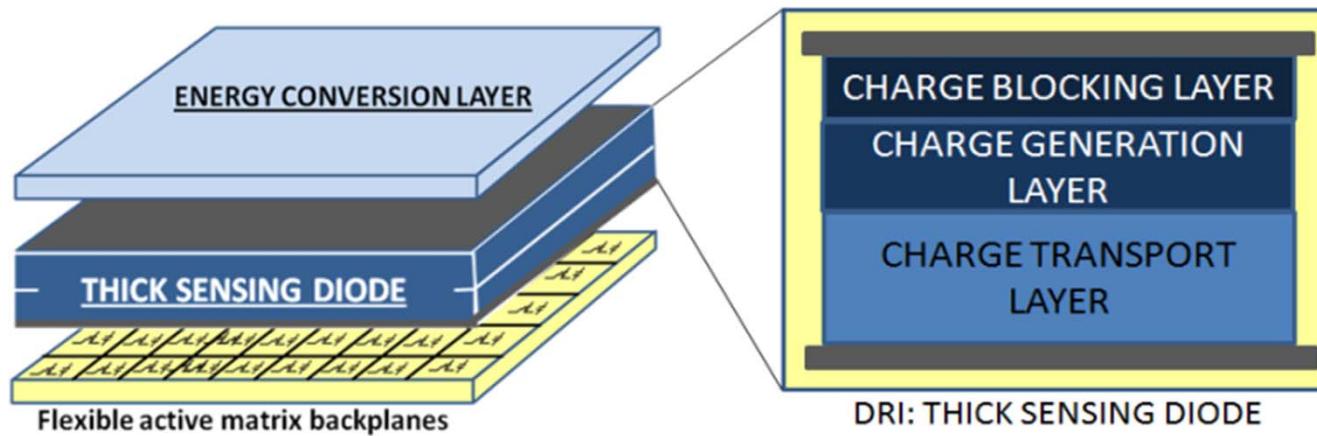
## Prototype neutron detector

- The output signal from the sensor element is a low voltage pulse with 10's ns width, with very high impedance due to the capacitive nature of the device.
- Charge amplifiers provide very high input impedance - they integrate weak charge pulses to convert them into voltage pulses with low impedance.



- [1] F. J. Ramirez-Jimenez et al., Nuclear Instruments and Methods in Physics Research A, 497, (2003), 577-583.  
[2] Bernd J. Pichler et al., IEEE Transactions on Nuclear Science, 48(6), (2001), 2370-2374.  
[3] HAMAMATSU, model H4083.

- Very large aperture at moderate cost based on AMLCD
- In-pixel electronics provide low capacitance for pixelated array
- Potential for high  $\gamma$ -ray rejection rate due to TFT array electronics
- Potential for fission neutron multiplicity measurements
- Potential for determination of directionality of the neutron source



*Thank You!*

